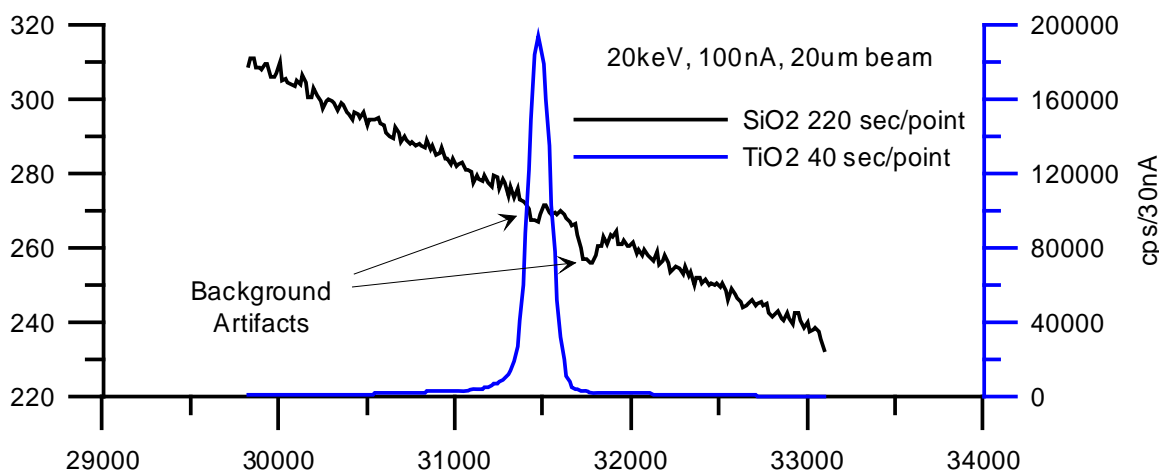


Blank Correction For Traces

A New Improved Accuracy Correction For Trace Elements

- Modern EPMA instruments equipped with low noise detectors, counting electronics and large area analyzing crystals can now routinely achieve sensitivities for most elements in the 10 to 100 PPM levels. However, because of various sample and instrumental artifacts in the x-ray continuum, absolute accuracy is more often the limiting factor for trace element quantification.



- A new “blank” correction developed for Probe for EPMA can be automatically applied to x-ray intensities during the matrix iteration process to correct for these systematic accuracy errors that are measurable at levels up to 50 PPM depending on particular spectrometer and crystal configurations.
- Trace concentration accuracies even at 500 PPM levels are improved significantly as the following graph demonstrates:

